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Terahertz Sensing and Imaging

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Message from the Guest Editors

Terahertz (THz) sensing and imaging methods have considerably evolved over the past decade, driven by a wide range of highly anticipated applications. This Special Issue of Applied Sciences will be dedicated to the development of THz imaging systems, with their components, their applications, and their methods.

Area of interest include (but are not limited to):

Source developments: pulse and continuous wave radiations;

Sensing methods: electric field measurements, energy measurements, optical sampling, signal amplification, near-field sensing, and light–matter interactions;

Analysis methods: image reconstruction, interferometry, computational imaging;

Applications: spectroscopy, 2D and 3D imaging.

Keywords: pulse and continuous terahertz (THz) wave radiations; Thz electric field measurements, energy measurements, optical sampling, signal amplification, near-field sensing, light–matter interactions; ultrafast THz spectroscopy; image reconstruction; interferometry; computational imaging; 2D and 3D THz imaging;



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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